

**Search Notes**

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Khoa D. Huynh

Applicant(s)/Patent under  
Reexamination

SHIRAI ET AL.

Art Unit

3751

**SEARCHED**

Class	Subclass	Date	Examiner
004	420.1 to 420.5, 433 to 448	7/16/2007	HK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR